

DUAL J-K FLIP-FLOP

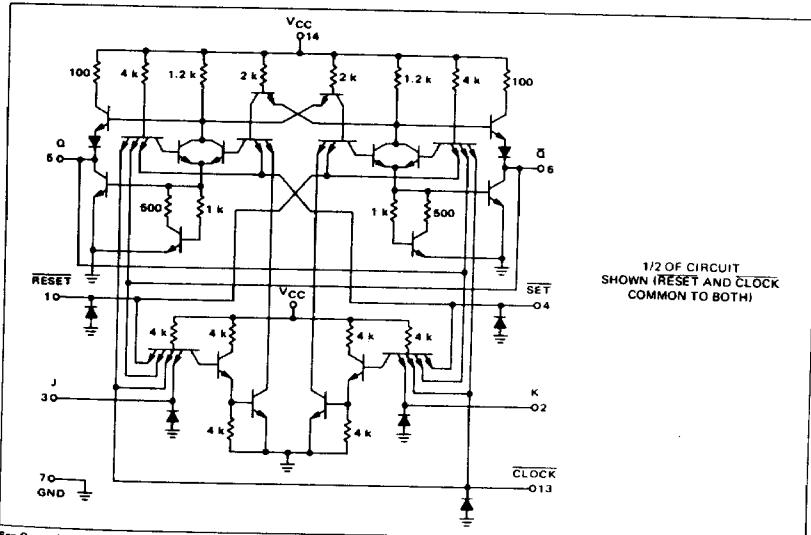
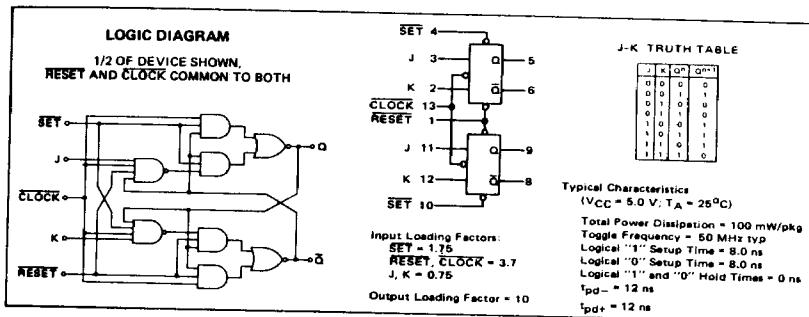
MTTL III MC3100/3000 series

**MC3161F • MC3061F
MC3161L • MC3061L,P**

This dual JK flip-flop triggers on the negative edge of clock. Each flip-flop is provided with a separate direct SET input in addition to the common direct RESET input. These direct inputs provide a means of resetting a group of flip-flops such as a register which may be followed by the presenting of a data pattern. The clock inputs for this device is common for both flip-flops, making it particularly useful in registers or other common clock applications.

Data may be applied to or changed at, the clocked inputs at any time during the clock cycle, except during the time interval between

the Setup and Hold times. The inputs are inhibited when the clock is low and enabled when the clock rises. The input steering network continuously responds to input information when the clock is high. The data state at the inputs throughout the interval between the Set-up and Hold time is stored in the flip-flop when the clock falls. Each flip-flop may be set at any time without regard to the clock state by applying a low level to the SET input. In addition, both flip-flops may be reset simultaneously by using the common RESET in a similar manner.

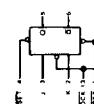


See General Information section for packaging.

MC3161F, MC3061F/MC3161L, MC3061L,P (continued)

ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one chip, two plus the inputs common to both chips. To complete testing, measure through the remaining inputs in the same manner.



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TEST CURRENT/VOLTAGE VALUES														
	mA							Volts						
	I_{OL}	I_{OH}	I_{in}	I_{on}	V_E	V_{HE}	V_F	V_B	V_{BE}	V_{max}	V_{CC}	V_{BEA}	V_{CEH}	
④ Test Temperature	-35°C	2.0	-3.0	-	-	-1.1	2.0	0.4	2.4	4.0	-	5.0	4.5	
MC3161	+25°C	2.0	-2.0	1.0	-10	1.1	1.8	0.4	2.4	4.0	7.0	5.0	4.5	
	+125°C	2.0	-3.0	-	-	0.8	1.8	0.4	2.4	4.0	-	5.0	4.5	
	0°C	2.0	-3.0	-	-	1.1	2.0	0.4	2.5	4.0	-	5.0	4.75	
MC3061	+25°C	2.0	-2.0	-10	1.1	1.8	0.4	2.5	4.0	7.0	5.0	4.75	5.25	
	+125°C	2.0	-3.0	-	-	0.9	1.8	0.4	2.5	4.0	-	5.0	4.75	
TEST CURRENT/VOLTAGE APPLIED TO PINS LISTED BELOW:														
MC3161 Test limits	MC3061 Test limits							Volts						
Input Forward Current	I_{FS}	3	-	-1.5	-1.5	-1.5	-1.5	I_{OL}	I_{OH}	I_{in}	I_{on}	V_E	V_{BE}	
	I_{PR}	2	-	-1.5	-1.5	-1.5	-1.5	-	-	-	-	3	-1.4.1.3	
	I_{PR}	1	-	-6.4	-6.4	-6.4	-6.4	-	-	-	-	2	-1.4.1.3	
	I_{PS}	4	-	-4.0	-4.0	-4.0	-4.0	-	-	-	-	1.5.9	-3.4.10.13	
	I_{PC}	13	-	-9.2	-9.2	-9.2	-9.2	-	-	-	-	4.6	-1.2.10.13	
Leakage Current	I_{RL}	3	-	50	50	50	50	I_{OL}	I_{OH}	I_{in}	I_{on}	V_E	V_{BE}	
	I_{RK}	2	-	50	50	50	50	-	-	-	-	6.8.13	-1.2.3.11.13	
	I_{RR}	1	-	200	200	200	200	-	-	-	-	3	-2.4	
	I_{RS}	4	-	150	150	150	150	-	-	-	-	2	-1.3	
	I_{RC}	13	-	300	300	300	300	I_{OL}	I_{OH}	I_{in}	I_{on}	V_E	V_{BE}	
Breakdown Voltage	BV_{In}	3	-	5.5	-	-	-	-	-	-	-	2.4	-1.4	
	BV_{In}	1	-	-	-	-	-	-	-	-	-	1.5	-	
	BV_{In}	4	-	-	-	-	-	-	-	-	-	3	-	
	BV_{In}	13	-	-	-	-	-	-	-	-	-	4	-	
Output Clamp Voltage	V_{OL}	5	-	0.4	0.4	0.4	0.4	V_{DC}	V_{DC}	I_{in}	I_{on}	V_E	V_{BE}	
	V_{OL}	2	-	-1.5	-1.5	-1.5	-1.5	-	-	-	-	4	-	
	V_{OL}	13	-	-	-	-	-	-	-	-	-	13	-	
	V_{OL}	14	-	-	-	-	-	-	-	-	-	13	-	
	V_{OL}	15	-	-	-	-	-	-	-	-	-	13	-	
	V_{OL}	3	-	-	-	-	-	-	-	-	-	3	-	
	V_{OL}	4	-	-	-	-	-	-	-	-	-	4	-	
	V_{OL}	13	-	-	-	-	-	-	-	-	-	13	-	
	V_{OL}	14	-	-	-	-	-	-	-	-	-	14	-	
	V_{OL}	15	-	-	-	-	-	-	-	-	-	15	-	
Short-Circuit Current (Total Device)	I_{SC}	5	-20	-65	-20	-65	-20	-65	-30	-65	-20	-65	-	
Power Requirements (Total Device)	Max. Power Supply Current	14	-	-	-	-	-	-	-	-	-	-	-	
	Power Supply Drain	14	-	30	-	30	-	30	-	30	-	30	-	

*Monomaurally ground pin prior to taking measurement. (If pin is also in another column, the pin must be returned to that voltage or current for measurement.)

MC3161F, MC3061F/MC3161L, MC3061L,P (continued)

OPERATING CHARACTERISTICS

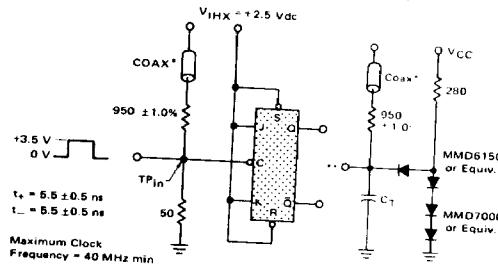
High state data must be present 12 ns prior to the fall of the clock and remain until Q goes after the clock falls.

The direct **SET** (individual) inputs and **RESET** (common) inputs may be used at any time without regard to the clock state. The flip-flop is set to the $Q = 1$ state by applying a low level to the **SET** input or reset to the $Q = 0$ state by applying a low level to the **RESET** input. If these inputs are not used they should be returned to a voltage between 2.0 and 5.5 Vdc.

Negative edge triggering. The input state during the time interval between the Setup and Hold times is stored in the flip-flop when the clock goes low.

Unused clocked inputs should be tied to the clock, to the internally connected output, or to a voltage between 2.0 and 5.5 Vdc.

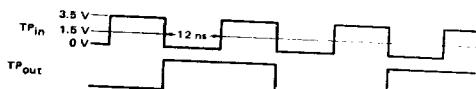
MAXIMUM CLOCK FREQUENCY TEST CIRCUIT



*The coax delays from input to scope and output to scope must be matched. The scope must be terminated in 50 ohm impedance. The 950-ohm resistor and the scope termination impedance constitute a 20:1 attenuator probe. Coax shall be CT-070-50 or equivalent.

$C_T = 25$ pF = total parasitic capacitance, which includes probe, wiring, and load capacitances.

VOLTAGE WAVEFORMS AND DEFINITIONS

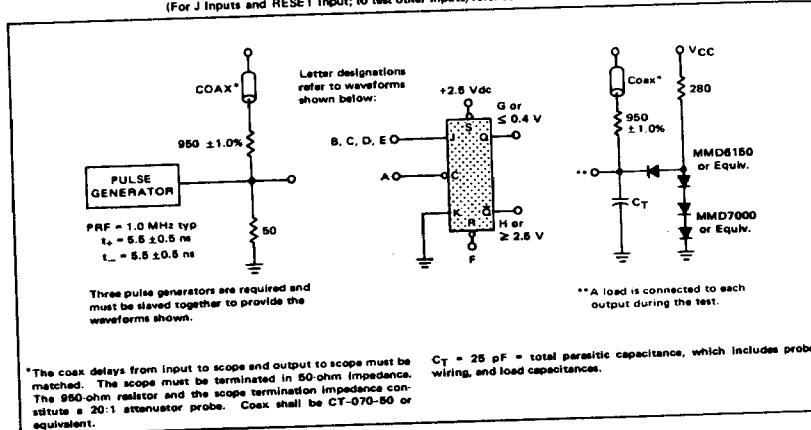


MC3161F, MC3061F/MC3161L, MC3061L,P (continued)

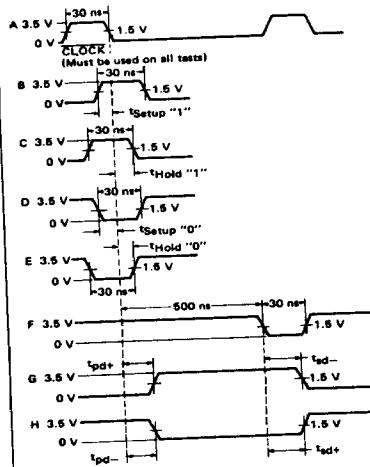
OPERATING CHARACTERISTICS (continued)

SWITCHING TIME TEST CIRCUIT

(For J Inputs and RESET Input; to test other inputs, refer to Test Procedures Chart)



VOLTAGE WAVEFORMS AND DEFINITIONS



TEST PROCEDURES CHART

TEST	INPUT						LIMITS (ns)
	J*	SAT*	RESET*	K*	O*	G*	
Setup "1" J	0	2.8 V	0	0nd	0	H	10
Hold "1" J	C	2.8 V	0	0nd	0	H	0**
Setup "0" J	D	2.8 V	0	0nd	SatV	2.8V	10
Hold "0" J	E	2.8 V	0	0nd	SatV	2.8V	0**
Setup "1" K	0nd	0	2.8 V	0	H	0	10
Hold "1" K	0nd	0	2.8 V	C	H	0	0**
Setup "0" K	0nd	0	2.8 V	0	SatV	2.8V	10
Hold "0" K	0nd	0	2.8 V	0	SatV	2.8V	0**
Setup	Delay from CLOCK to G during Setup "1" J test. Delay from CLOCK to G during Setup "0" J test.						10
Hold	Delay from CLOCK to G during Setup "1" K test. Delay from CLOCK to G during Setup "0" K test.						10
Setup	Delay from EDGE to G during Setup "1" J test. Delay from EDGE to G during Setup "0" J test.						10
Hold	Delay from EDGE to G during Setup "1" K test. Delay from EDGE to G during Setup "0" K test.						10
Setup	Delay from SAT to G during Setup "1" J test. Delay from SAT to G during Setup "0" J test.						10
Hold	Delay from SAT to G during Setup "1" K test. Delay from SAT to G during Setup "0" K test.						10
Setup	Delay from RESET to G during Setup "1" J test. Delay from RESET to G during Setup "0" J test.						10
Hold	Delay from RESET to G during Setup "1" K test. Delay from RESET to G during Setup "0" K test.						10

*Letters shown in these columns refer to waveforms shown at the left.

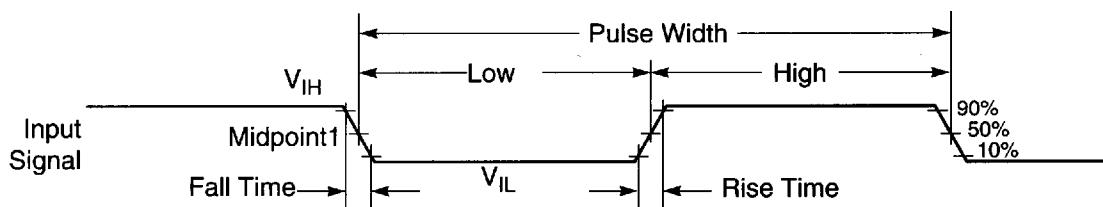
**Value is typically a negative number.

Specifications

AC Electrical Characteristics

AC ELECTRICAL CHARACTERISTICS

The timing waveforms in the AC Electrical Characteristics are tested with a V_{IL} maximum of 0.5 V and a V_{IH} minimum of 2.4 V for all pins, except EXTAL, RESET, MODA, MODB, and MODC. These pins are tested using the input levels set forth in the DC Electrical Characteristics. AC timing specifications that are referenced to a device input signal are measured in production with respect to the 50% point of the respective input signal's transition. DSP56002 output levels are measured with the production test machine V_{OL} and V_{OH} reference levels set at 0.8 V and 2.0 V, respectively.



Note: The midpoint is $V_{IL} + (V_{IH} - V_{IL})/2$.

AA0179

Figure 2-1 Signal Measurement Reference